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- From discussions at PIXEL2022: TSMC is trying to push designs away from 65nm and people start questioning the long-medium term availability of this technology.

The TSMC 28nm technology is the most performant planar mainstream solution that evolved through the years due to constant enhancements in the manufacturing process.

It supports a wide range of applications, including CPUs, GPUs, high-speed networking chips, smart phones, APs, tablets, home entertainment, consumer electronics, automotive and IoT.

It mainly uses High-k Metal Gate (HKMG) gate-last technology. Compared to the gate-first technology, the gate-last offering provides more advantages, including lower leakage current and better chip performance.

28nm CMOS HPC Logic, RF

Technology characteristics

Shrink technology: YES

Core voltage: 0.9V

I/O voltage: 1.8V

Shallow Trench Isolation (STI)

Wells: Retrograde twin well for low well sheet resistance and better latch-up behavior.

Triple well, Deep N-Well in option

Dual Gate Oxide

Vt options: ulvt, lvt, svt, hvt, uhvt, ehvt
5V HVMOS

HighRes resistors

Temperature range: -40C to 125C

of metals: 5 to 10 Cu + ALRDL

Interconnect dielectric: ELK

Top metal: 8.5KA, 11.5KA, 35KA

CMP on STI, contact, via and passivation

MoM capacitor

Passivation: dual layers

Options that need special attention	SRAM Cell Vt's: maximum of 4 VT types in one design.
Wafer size	12 inch
Deliverables	100 dies, no wafer
Design tools	PDK: TSMC iPDK
Simulation tools	HSPICE, Eldo, Spectre
Verification tools DRC	Cadence, Siemens EDA, Synopsys
Verification tools LVS	Cadence, Siemens EDA, Synopsys
Parasitic extraction tools	Cadence, Siemens EDA, Synopsys
P&R tools	Cadence, Siemens EDA, Synopsys
Foundry IP	12-track / 9-track / 7-track core cell libraries, multi-vt's 0.9V/1.8V hybrid staggered (fail-safe digital and regular analog) I/O library SRAM compilers by TSMC , ARM, Synopsys
MPW block size	6mm ² (on silicon)
Mini@sic characteristics	Supported Min area: 1mm ² (post-shrink) <u>mini@sic Technology options</u>

Other technical details

- Lower metal layers: $0.45\Omega/\square$
(UMC110: M1= $0.17\Omega/\square$; M2= $0.13\Omega/\square$)
- fT above 300 GHz

Recommended 28 nm mini@sic options

Metal Scheme	9M_5XIYIZIU UT-ALRDL
Flip-Chip/bumping	Not supported in the common flow. Please contact eptsmc@imec.be .
Allowed devices	<p>(1) ultra low Vt = {VTUL_N OR VTUL_P} (2) low Vt = {VTL_N OR VTL_P} (3) high Vt = {VTH_N OR VTH_P} (4) ultra high Vt = {UHVT_N OR UHVT_P}</p> <p>Standard devices are by default allowed Contact eptsmc@imec.be if other Vt's are needed.</p>
SRAM/ ULL SRAM	Not supported in the common flow. Please contact eptsmc@imec.be .
AP thickness	28kÅ
Backlapping thickness	11 mils

Important note:

Always use the T-N28-CR-SP-029 (mmWave ULL) PDK with flavor RF HPC+ 0.9/1.8V.
Sub-dicing of multiple sub-chips is not possible.

Restrictive Design Rules

- Starting from the 28 nm technological node, the **design rules are becoming much more complex** in terms of device usage, density requirements and physical design limits.
- Poly and metal density must be kept very uniform across the die in order to fabricate the minimum channel length devices in a reliable way.
- Beside limits on the minimum and maximum poly density, there are also rules for the maximum poly area per device finger: large area devices must be fragmented
- Gate orientation of all the devices must be uniform across the whole wafer, circuits rotation is strictly prohibited.
- Maximum transistor gate area, maximum transistor width W and length L : in 28 nm the maximum W and L for a single device finger are $3\mu\text{m}$ and $1\mu\text{m}$, respectively.

Radiation Hardness

- Enclosed-layout devices not possible
- Circuitual approaches more challenging (and not always enough)
- Ultra-scaled technologies, and especially the 28 nm, results to be more radiation resistant than the others
 - radiation damage is proportional to gate oxide volume
 - gate dielectric has been replaced with high-k materials

mini@sic:

- HPC: 1 run/year
- HPC+: 3 runs/year

MPW:

- HPC/HPC+: 12 runs/year

RadTol Analog IP blocks library

EP R&D

Analog IP blocks design - responsible **Raphael Ballabriga** (WP5.2)

BANDGAP VOLTAGE REFERENCE & TEMP MONITOR

**G. Traversi** (Bergamo/Pavia) / INFN Falaphel project

Design completed. Submitted in Jan 2022

https://asic-support-28.web.cern.ch/docs2/slvs_tx_rx

DIGITAL TO ANALOG CONVERTER (8-BIT)

**Markus Piller** (DOCT, CERN EP-R&D WP5)

Design completed. Submitted in Jan 2022

datasheet https://asic-support-28.web.cern.ch/docs2/slvs_tx_rx

DIFFERENTIAL LINE DRIVERS AND RECEIVERS

**Franco Bandi** (CERN EP-R&D WP5)

Design completed. Submitted in Jan 2022

https://asic-support-28.web.cern.ch/docs2/slvs_tx_rx

RAIL TO RAIL OPERATIONAL AMPLIFIER

**Jan Kaplon** (CERN EP-ESE)

Design completed. To be submitted in Dec. 2022.

https://asic-support-28.web.cern.ch/docs2/slvs_tx_rx

ADC FOR MONITORING (12-BIT)

**Tobias Hofmann** (CERN EP-R&D WP5)

In progress

https://asic-support-28.web.cern.ch/docs2/slvs_tx_rx

RAIL TO RAIL OPERATIONAL AMPLIFIER

**Markus Piller** (CERN, DOCT)

In progress

https://asic-support-28.web.cern.ch/docs2/slvs_tx_rxMore details in the presentation by Franco Bandi: <https://indico.cern.ch/event/1207114/>



RadTol Analog IP blocks library

EP R&D

R&D

Analog IP blocks design - responsible **Raphael Ballabriga** (WP5.2)

ANALOG PLL

**Tobias Hofmann** (CERN EP-R&D WP5)

In progress

https://asic-support-28.web.cern.ch/docs2/slvs_tx_rx

DIGITAL PLL

**Markus Piller** (DOCT, CERN EP-R&D WP5)

In progress

https://asic-support-28.web.cern.ch/docs2/slvs_tx_rx

Powering solutions design - responsible **Stefano Michelis** (WP5.2b)

DCDC CONVERTER

**Stefano Michelis** and **Giacomo Ripamonti** (CERN EP-ESE)

In progress

https://asic-support-28.web.cern.ch/docs2/slvs_tx_rx

LDO

**Stefano Michelis** and **Giacomo Ripamonti** (CERN EP-ESE)

In progress

https://asic-support-28.web.cern.ch/docs2/slvs_tx_rx

More details in the presentation by Franco Bandi: <https://indico.cern.ch/event/1207114/>

RadTol Analog IP blocks library

Fundamental IP blocks - responsible ASIC Support Service

RADIATION TOLERANT ESD PROTECTIONS



Outsourced to SOFICS by the CERN ASIC Support



Design completed. Submitted in Jan 2022 for radiation characterization.



https://asic-support-28.web.cern.ch/docs2/slvs_tx_rx

RADIATION TOLERANT CMOS IO PAD



outsourced to SOFICS by the CERN ASIC Support



In progress. Radiation characterization will follow.



https://asic-support-28.web.cern.ch/docs2/slvs_tx_rx

SRAM MEMORIES



Compilers purchased from the Foundry by the CERN ASIC Support



We can distribute precompiled memory upon request



Submitted in Jan 2022. Radiation characterization completed.



https://asic-support-28.web.cern.ch/docs2/slvs_tx_rx

EFUSES



IP block purchased from the Foundry by the CERN ASIC Support



Radiation characterization will follow.



https://asic-support-28.web.cern.ch/docs2/slvs_tx_rx

- K. Kloukinas:

«A full maskset with all technology options and maximum metal stack (9 metals) is **1.2 million USD**».

As a reference:

110nm UMC: 150,000 USD

65nm TSMC: 500,000 USD

MPW are on the contrary rather cheap, I don't have a number but I think ~40,000 for the minimum size. MiniAsics are possible.

- We should receive the NDA to sign vvery soon (today?)
- It should go much quicker than with 65nm: